



EMIF11-10002C4

9 LINES EMI FILTER AND ESD PROTECTION

IPAD™

MAIN PRODUCT CHARACTERISTICS:

Where EMI filtering in ESD sensitive equipment is required :

- Mobile phones and communication systems
- Computers, printers and MCU Boards

DESCRIPTION

The EMIF11-10002C4 is a highly integrated devices designed to suppress EMI/RFI noise in all systems subjected to electromagnetic interferences.

This device includes 9 EMI filters & ESD protection circuitry which prevents the device from destruction when subjected to ESD surges up 15kV. In addition, the EMIF11 integrates 2 other ESD protection for data and 1 ESD protection for V_{CC}.

BENEFITS

- EMI symmetrical (I/O) low-pass filter
- High efficiency in EMI filtering
- High efficiency in ESD suppression (IEC61000-4-2 level 4)
- High reliability offered by monolithic integration
- High reducing of parasitic elements through integration & wafer level packaging
- QFN 4x4mm package for an easy layout

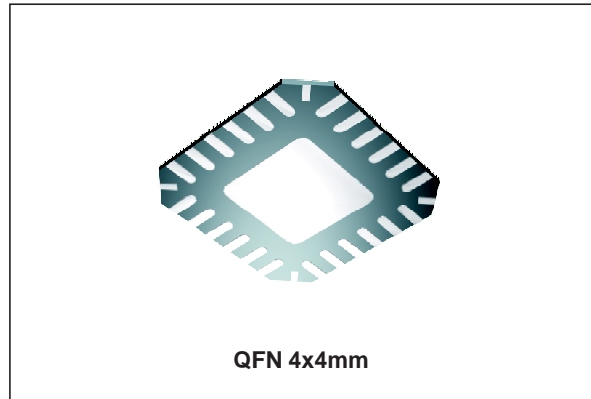
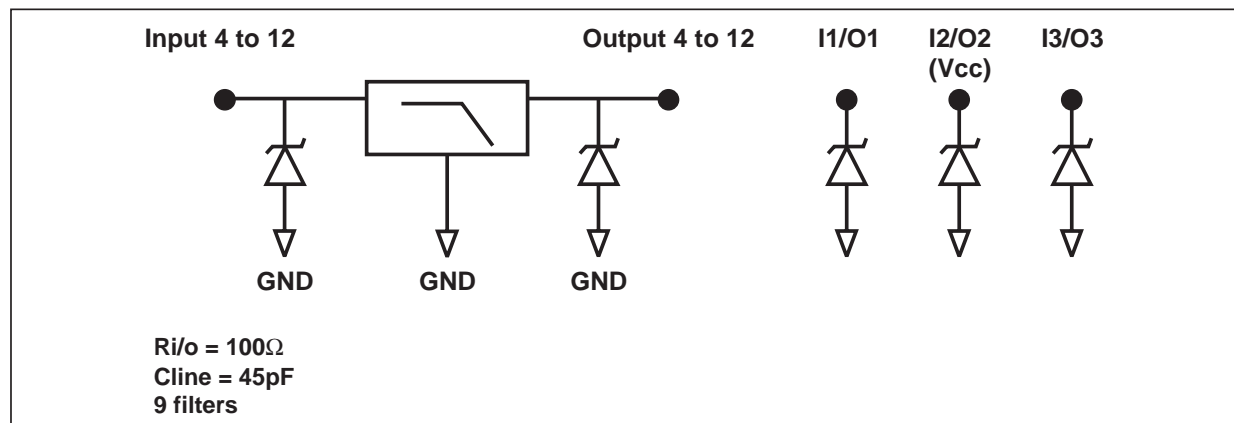
COMPLIES WITH THE FOLLOWING STANDARDS:

IEC61000-4-2

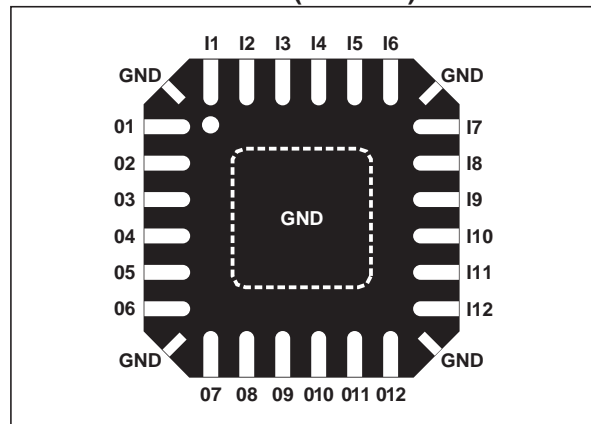
Level 4	on input pins	15kV	(air discharge)
		8 kV	(contact discharge)

MIL STD 883E - Method 3015-7 Class 3

BASIC CELL CONFIGURATION



PIN CONFIGURATION (ball side)



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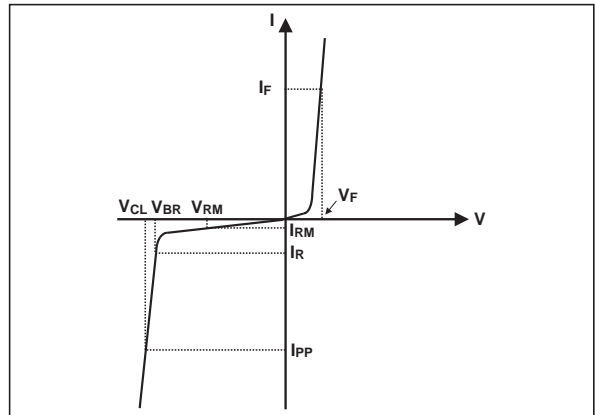
EMIF11-10002C4

ABSOLUTE RATINGS (limiting values)

Symbol	Parameter and test conditions	Value	Unit
T_j	Maximum junction temperature	150	°C
T_L	Maximum lead temperature for soldering during 10s	260	°C
T_{op}	Operating temperature range	-40 to +85	°C
T_{stg}	Storage temperature range	-40 to +85	°C

ELECTRICAL CHARACTERISTICS ($T_{amb} = 25\text{ °C}$)

Symbol	Parameter
V_{BR}	Breakdown voltage
I_{RM}	Leakage current @ V_{RM}
V_{RM}	Stand-off voltage
$R_{I/O}$	Series resistance between Input & Output
C_{line}	Input capacitance per line



Symbol	Test conditions	Min.	Typ.	Max.	Unit
V_{BR}	$I_R = 1\text{ mA}$	6	7	8	V
I_{RM}	$V_{RM} = 3\text{V per line}$			1	μA
$R_{I/O}$	Cells 4 to 12	90	100	110	Ω
C_{line}	$V_R = 0\text{V}$ (Cells 4 to 12)		45		pF

Fig. 1: S21(dB) attenuation measurement and Aplac simulation.

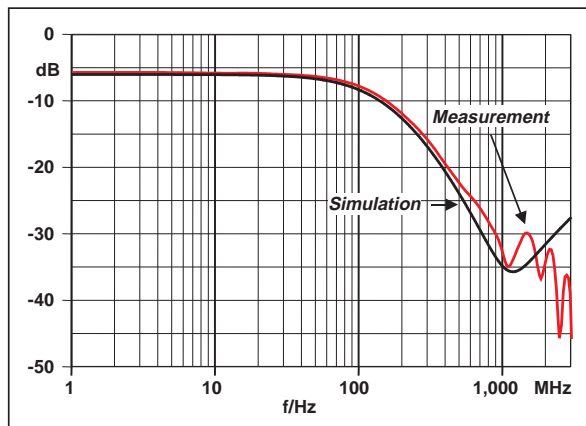


Fig. 2: Analog crosstalk measurements.

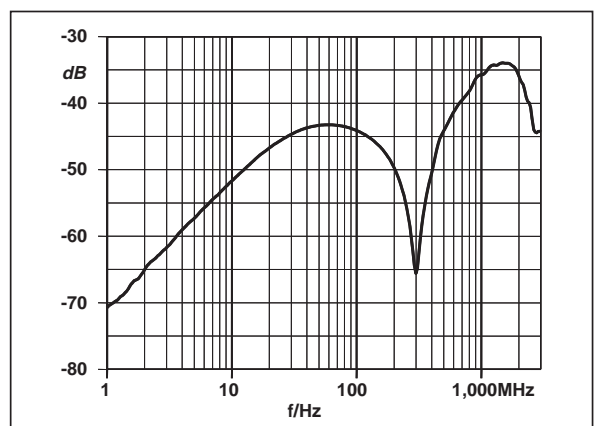


Fig. 3: Digital crosstalk measurement.

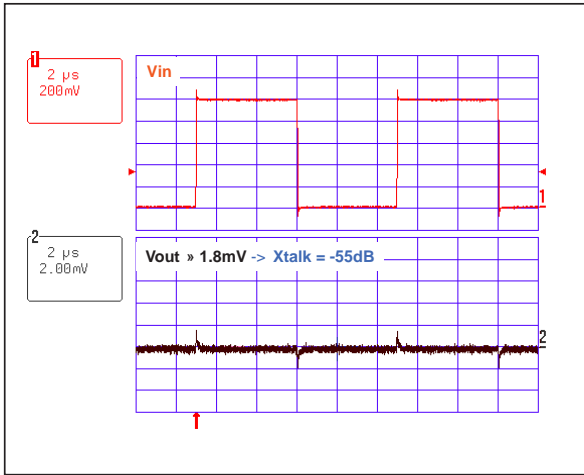


Fig. 4: ESD response to IEC61000-4-2 (+15kV air discharge) on one input V(in) and on one output V(out).

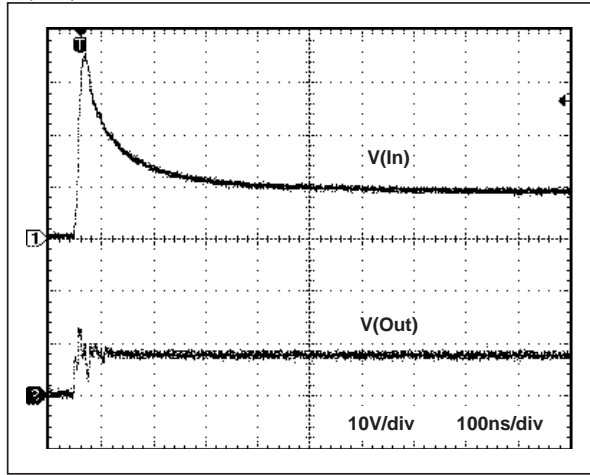


Fig. 5: ESD response to IEC61000-4-2 (-15kV air discharge) on one input V(in) and on one output V(out).

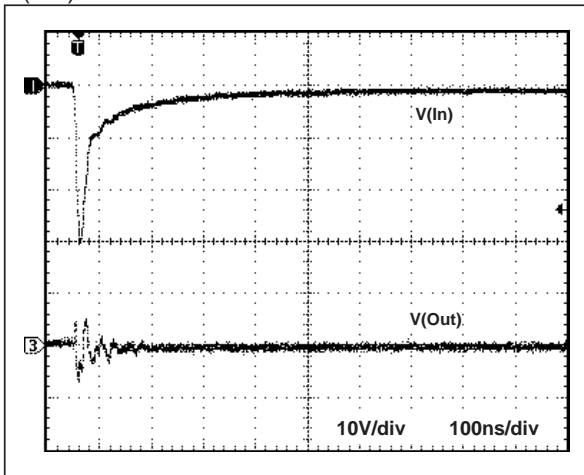
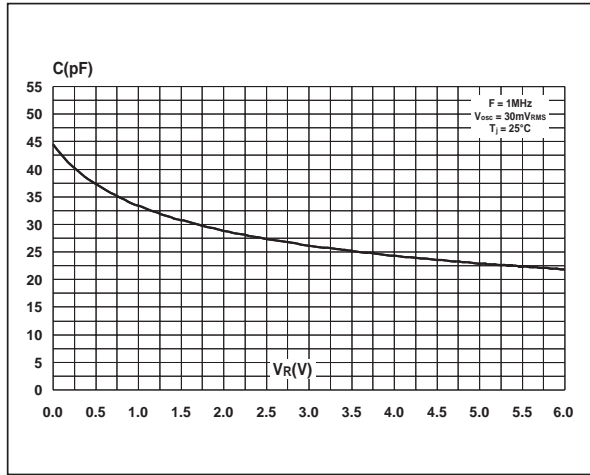
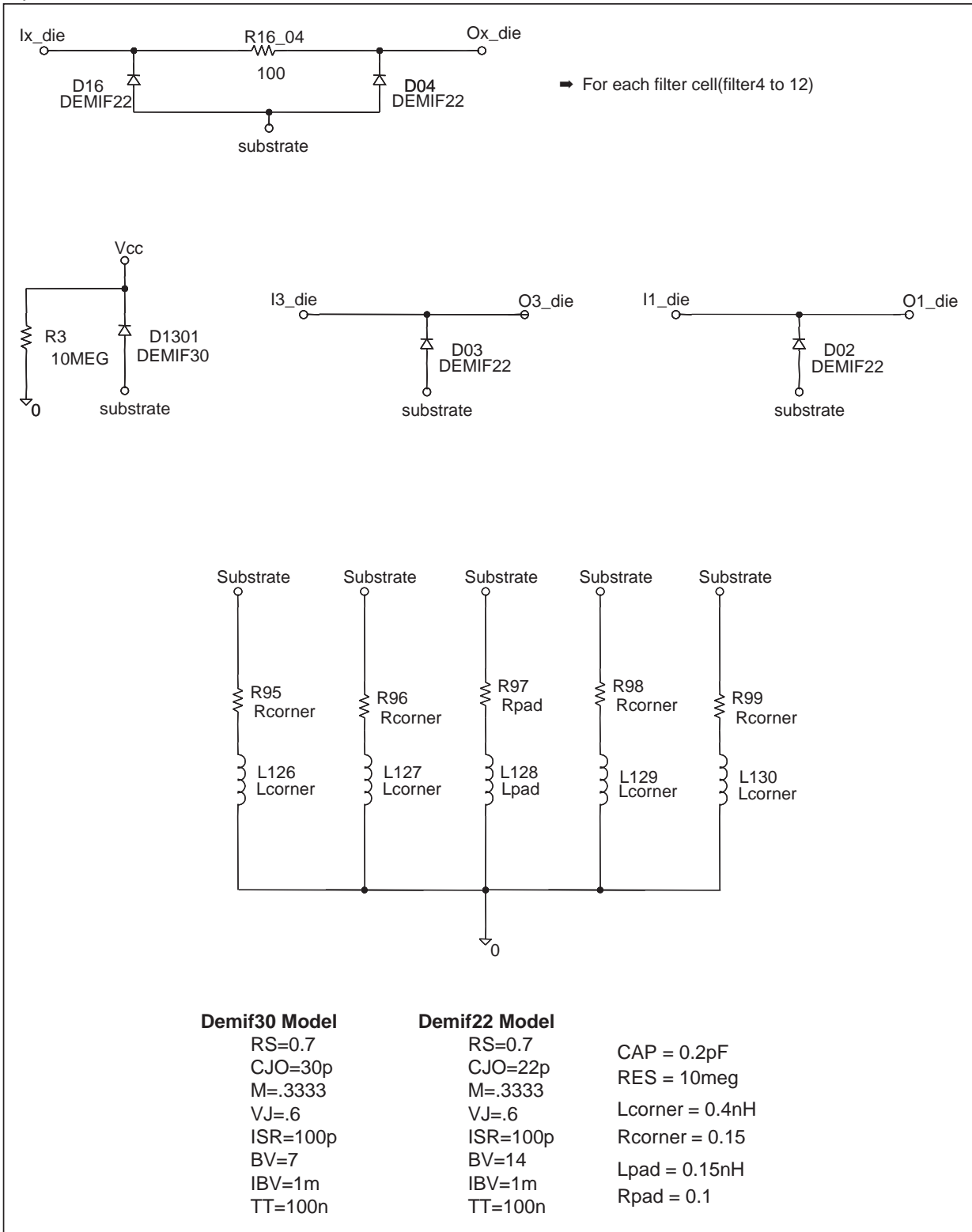


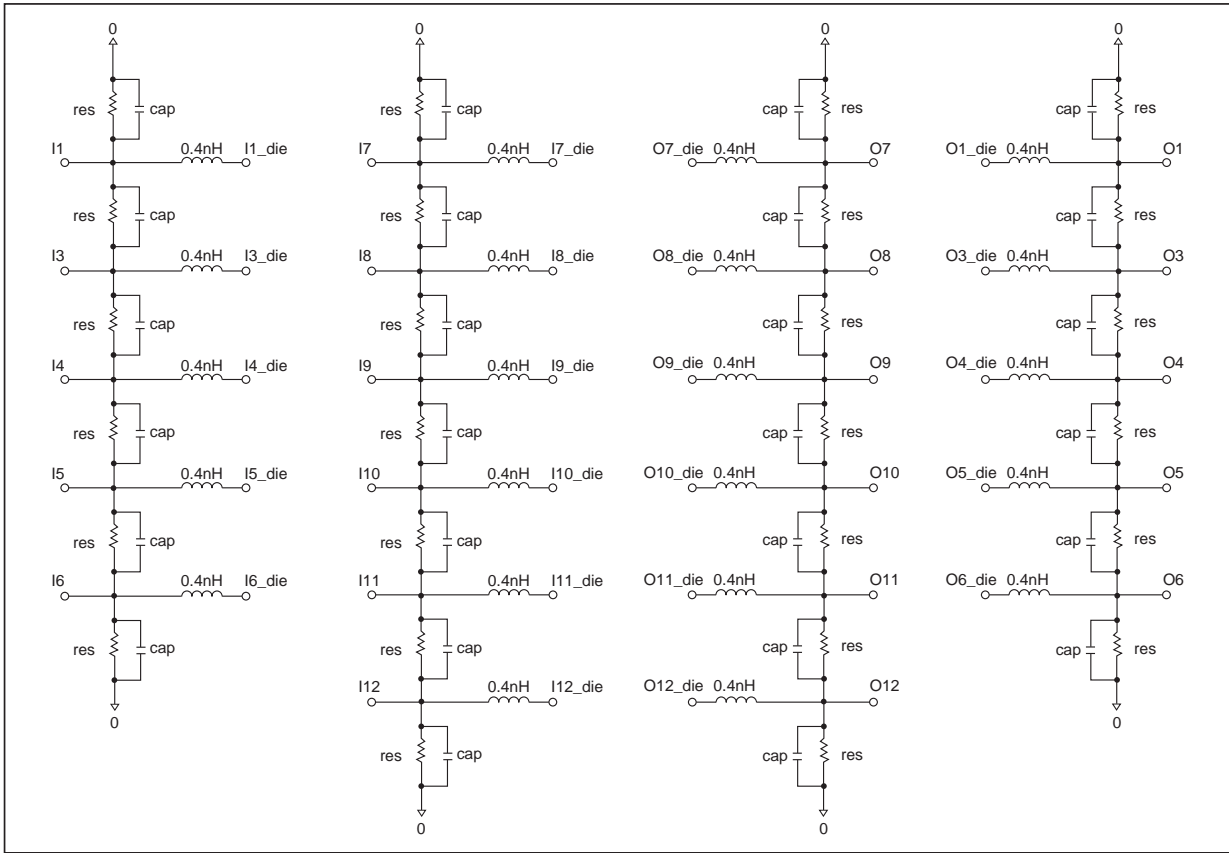
Fig. 6: Line capacitance of filter cells versus applied voltage.



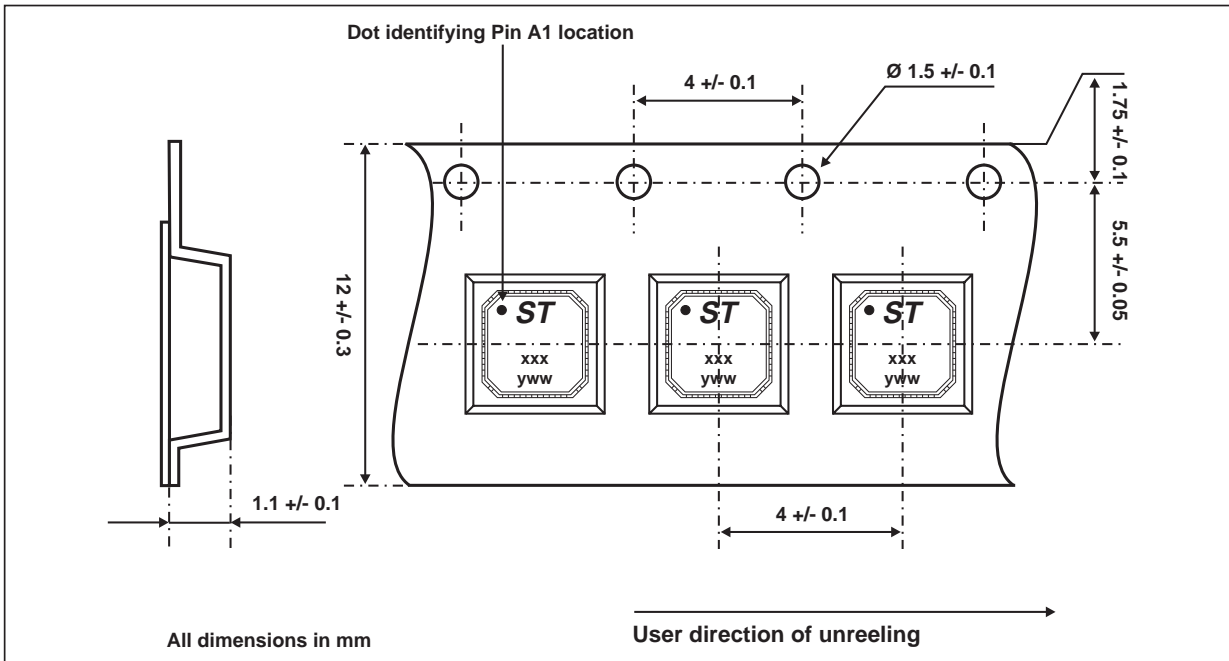
Aplac model.



Aplac model (continued).



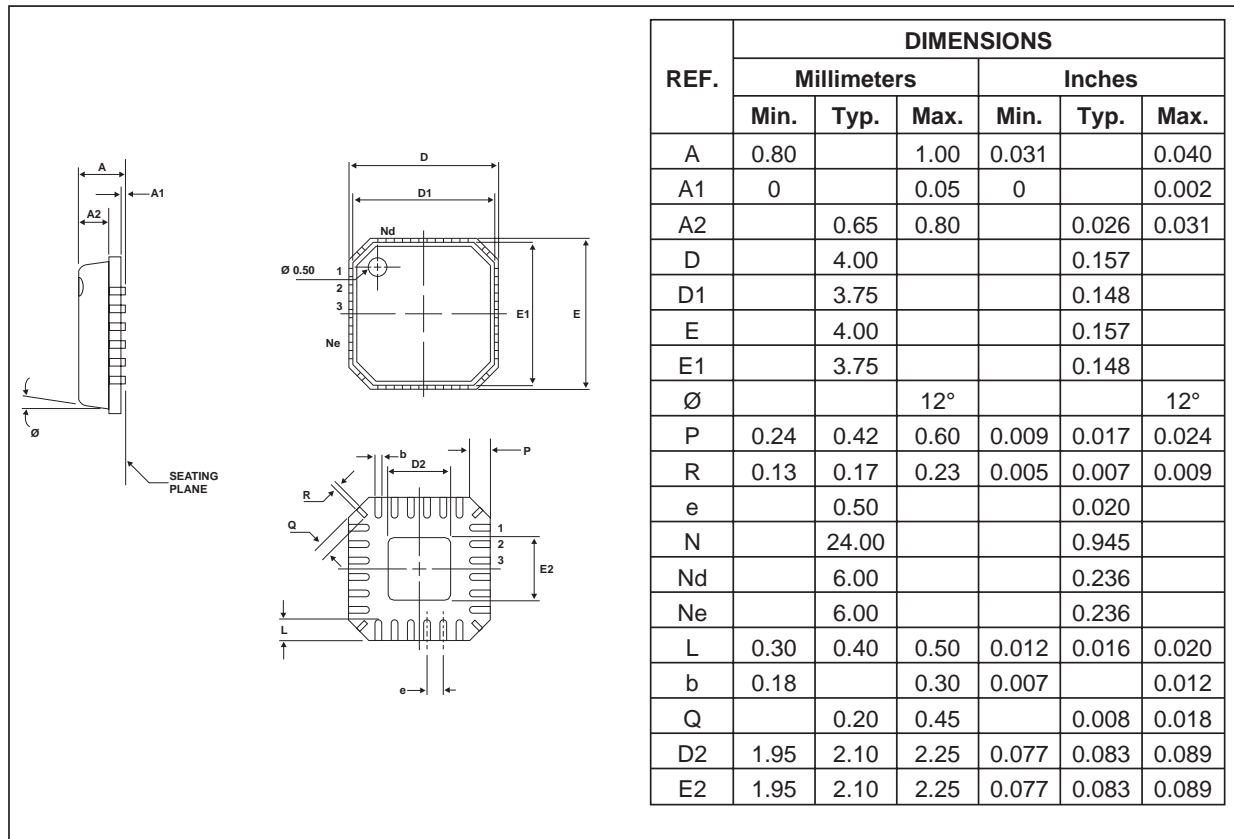
PACKING



EMIF11-10002C4

PACKAGE MECHANICAL DATA

QFN 4x4mm



OTHER INFORMATION

Ordering code	Marking	Package	Weight	Base qty	Delivery mode
EMIF11-10002C4	E11U	QFN 4x4mm	235 mg	4000	Tape & reel (7")

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